

**Notice of References Cited**

Application/Control No.

09/552,292

Applicant(s)/Patent Under  
Reexamination  
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Examiner

Kenneth A Gross

Art Unit

2122

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"How Debuggers Work", by Jonathan B. Rosenberg, 1996, pages 136-139
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.